**EEE 264 (Electronic Circuits Sessional)**

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| 05 |

**EXPT. NO.**

**NAME OF THE EXPERIMENT:**

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| STUDY OF BJT BIASING CIRCUITS |

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| **Group No.** | **05** |
| **Writer’s Roll** | **1705027** |
| **Section** | A-1 |
| **Department** | CSE |
| **Other Group Members** | 1705025  1705026  1705028  1705029  1705030 |
| **Date of Performance:** |  |
| **Date of Submission:** |  |